MONTROSE Technologies Inc.

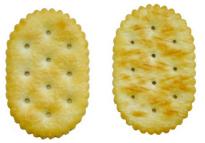
Automated Inspection & Intelligent Material Handling for Crackers / Wafers

Montrose inspection and handling systems provide a complete inspection, rejection, and handling solution created just for cracker (biscuit) manufacturing lines. Receive comprehensive statistical analysis of variability while removing human involvement from inspection and rejection.

A high speed, turnkey system that allows you to:

- 1. Assure quality on a 100% monitoring basis.
- 2. Remove individual defective and non-conforming product from the line.
- 3. Monitor process statistics to pinpoint causes of waste.
- 4. Rapidly recognize a positive ROI by improving quality, reducing waste, and automating production in previously labor-intensive areas.

Solution Components	SnapQC	FocalPoint	MT Series
3D & True Color Inspection	\checkmark	\checkmark	\checkmark
Bottom Color Inspection	~		~
Automated Rejection			$\overline{\checkmark}$
Weight	\checkmark		
Statistical Analysis and Reporting	~	~	~
NEMA 4X		$\overline{}$	~
Sanitary Design	\checkmark	\checkmark	\checkmark





> Isolate and Eliminate Sources of Waste

Automated inspection provides real-time and historical information on fault, and out-of-spec conditions, allowing you to isolate the issues causing the most waste by shift, product, line, and plant. The measurement results will also make it easier to reach consistent quality when developing new products or when formulation changes are made.

Analysis Type	Example Faults	Impact on Customer or Plant	Rejection Capability	Statistical Analysis
Geometrical Analysis		0 - 100% fully under plant control	Worst Fault Pareto	
Ova Dou Miss	Ovality	Customer complaints	plant control	Reporting
	Doubles Misshaped Warped	Handling problems, such as jamming at packaging		Dashboard
Color Analysis	Under- or over-baked Visible debris	Consumer complaints	0 - 100% fully under plant control	Worst Fault Pareto
	Foreign material	Product rejection		Reporting
		Process Optimization		Dashboard

> Measure, Reject, Analyze

The **MT Series inspection system** uses 3-D vision to identify a wide range of cracker defects, including those dimensional defects that can cause disruptions with penny stacking and packaging. The automatic removal of the defective cracker(s) will reduce product waste, reduce production interruptions, and increase productivity.

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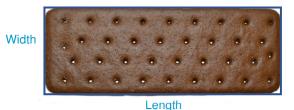
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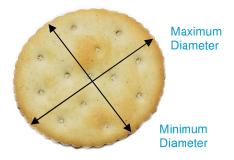
> Common Height Analysis



Profile height calculations are based on hundreds of individual height values gathered on every product, which leads to a measurement accuracy of ±0.5mm. Mean Height, Height Symmetry, and Center Height are other common measurements applied to crackers.

> Common 2-D Analysis



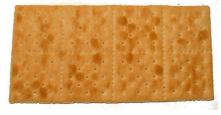


Two dimensional calculations are based on an accurately defined perimeter, which is imaged by both overhead cameras. 2-D measurement accuracy is ±0.5mm. Mean Diameter, Roundness, Surface Area, and Volume are other common measurements applied to crackers.

> Common Color Analysis



Average Color



True color calculations are measured in various units such as $L^*a^*b^*$ and BCU, which <u>quantify small variations of bake</u> <u>color</u>.

> Common Fault Analysis



Warped







Only common examples have been pictured. There are many standard measurements that can be used, individually or combined within formulae, to qualify your product. All visible product characteristics and faults can be quantified.